

# ROC286 SERIES PERFECTRON SYSTEM RELIABILITY/ENVIRONMENT TEST PLAN

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Version History				
Document Release	Date	Change Item	Remarks	
V1.0	11/25/2019	Preliminary release		



	System Configuration				
Motherboard	MITAC PH14FEI				
CPU	Intel® Core™ i7-8700T Processor 2.4 GHz				
РСН	Intel Q370				
Memory	Innodisk 8GB SOD DDR4 2133				
SATA port1	InnDisk 3MG2 SSD 64G				
SATA port2	Apacer SSD 256G				
LAN1	Intel®i210 GbE LAN				
LAN2	Intel® i219 GbE LAN				

	System Test Items Configuration _ Test Results Definition						
No.	Test Item	Otro	System Sample				
No.	rest item	Qty	No.1	Remark			
1.	AC Input Voltage Fuctuation Test	1	PASS				
2.	IO Function Test	1	PASS				
3.	Operation System & Drivers Test	1	PASS				
4.	Power Consumption	1	PASS				
5.	I/O Integrated Stress Test	1	PASS				
6.	Temperature Alternate Operation Test	1	PASS				
7.	High Temperature Operating Test	1	PASS				
8.	High Temperature and Humidity Operating Test	1	PASS				
9.	Low Temperature Operation Test	1	PASS				
10.	High Temperature Power ON/OFF Test	1	PASS				
11	Low Temperature Power ON/OFF Test	1	PASS				
12	Thermal Measurement	1	PASS				



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- 1. AC Input Voltage Fluctuation Test
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- 6. Temperature Alternate operation Test
- 7. High Temperature Operating Test
- 8. High Temperature and Humidity Operating Test
- 9. Low Temperature Long Thermal Operation Test
- 10. High Temperature Power ON/OFF Test
- 11. Low Temperature Power ON/OFF Test
- 12. Thermal Measurement



# 1.AC Input Voltage Fluctuation Test

Test Purpose	To evaluate the influence on the EUT under voltage fluctuation from the AC power Source	Test Result	PASS		
Test Equipment	Passmark USB3.0 Plug				
Quantity Tested	Minimum 1 Set				
Test Condition	Test Software: Passmark BURN-IN Test Program under Microsoft Windows 10  Test Procedure: 1. Adjust AC power source to upper limit 2. Turn on the system and perform the function test with 100% loading for a period of 1 hour at least 3. Check the functions of the system and record it 4. Change AC power source to lower limit 5. Repeat steps 2~3				
Test Criteria	All units must be pass 1 hour Burn-In test program, withou EUT must be no damage or safety problem occurred.	t any error occu	r. The		
Test Log / Photo	Sensor Control Top Bill Configuration Text Outs Text Help  Top Control Top Bill Control Text Con	- 9V 0.744 V 0.744 V 1974 V 19	D.248 V 2.744 V 2.744 V 3.444 PPM 444 PPM 445		



## 2. IO Function Test

Item		Criteria	Result	Note
SATA Port 1		SATAIII Onboard SSD device Run PassMark 20 minutes with all disks	Pass	
SATA Port 2		SATAIII Onboard SSD device Run PassMark 20 minutes with all disks	Pass	
LICD1		can use any USB device	Pass	
USB1		Loopback Plugs for USB 2.0 Trouble shooting and Testing	Pass	
USB2		can use any USB device	Pass	
USB2		Loopback Plugs for USB 2.0 Trouble shooting and Testing	Pass	
LICD1		can use any USB device	Pass	
USB1		Loopback Plugs for USB 3.1 Trouble shooting and Testing	Pass	
LICD2		can use any USB device	Pass	
USB2		Loopback Plugs for USB 3.1 Trouble shooting and Testing	Pass	
LICD2		can use any USB device	Pass	
USB3		Loopback Plugs for USB 3.1 Trouble shooting and Testing	Pass	
LICD4		can use any USB device	Pass	
USB4		Loopback Plugs for USB 3.1 Trouble shooting and Testing	Pass	
COM1		Check work well	Pass	
COM2		Check work well	Pass	
	DP1		Pass	
Display output	DP2	Check work well	Pass	
	HDMI		Pass	
LAN port1		Intel i210 LAN Function Test	Pass	
LAN port2		Intel i219 LAN Function Test	Pass	
Power SWITCH		Check work well	Pass	
LINE-OUT/ MIC in		Check work well	Pass	
Power supply on/off		Check work well	Pass	
HDD slot 1/2		Check work well	Pass	
Power Led		Check work well	Pass	
HDD Led		Check work well	Pass	
AC in 110V		Check work well	Pass	



3.Operation System & Drivers Test

Publisher	Package & Version	DUT-1	Note
Microsoft OS	DOS98	Pass	
Microsoft OS	Microsoft Windows 10 64Bit	Pass	

Driver and Application software	Version / Details	DUT-1	Note
INF	10.1.1.42	Pass	
VGA	igfx_win10_100.7000	Pass	
Audio	6.0.1.7541	Pass	
LAN	12.13.17.7	Pass	
ME	ime12	Pass	



# **Display Function Test**

DP Test							
	1. Use 800x600 1024x768 1280x720(or highest solution) and 16&32 bit to test display correctly. 2. Check display with test pattern 3. check display can nothas any cross-color, water wave, and ghost.						
resolution	800x600, 60Hz	800x600, 75Hz	1024x768, 60Hz	1024x768, 75Hz	1280x720, 60Hz	1280x720, 75Hz	1920x1080, 60Hz
DP1	PASS	PASS	PASS	PASS	PASS	PASS	PASS

			Resolution t	est
Monitor	ASUS 27" P	B278Q , Maxir	num resolution: 2560 x 1440	
Model	ASUS 23" P	A238, Maximu	m resolution: 1920 x 1080	
Resolution	D	P1	DP2	DP3
1024 x 768		✓	<b>✓</b>	✓
1280 x 1024		✓	<b>√</b>	<b>√</b>
1366 x 768		✓	<b>√</b>	<b>√</b>
1920 x 1080		✓	<b>√</b>	<b>√</b>
1920 x1200		✓	<b>√</b>	<b>√</b>
2560 x 1440		✓	<b>√</b>	✓



## 4. Power Consumption

	_
Test Purpose	To measure power consumption of the EUT during operation/suspend mode/power off mode
<b>Quantity Tested</b>	Minimum 1 Set
Test Procedure	<ol> <li>Turn on the power source and set the output voltage frequency following to the test specification</li> <li>Connect the Power Meter between EUT and power source</li> <li>Connect maximum quantity of external devices on all I/O (ex. USB, COM, etc), and have the full loading status on each device</li> <li>Turn on the EUT and set the EUT on each consumption mode</li> <li>Measure and record the power consumption value shown on Power Meter as Watt</li> </ol>
Test Criteria  1. The Max. power consumption value must not exceed the output ability of used pow supply, the derating while in high temperature environment must also to be considered. By following the EuP LOT 6 requirement, the power consumption of the standby multimited 1.0 Watt (for w/o WOL model) and 1.7Watt (for w/ WOL model)	

Item	Device Information (Full load)		
CPU	Intel® Core™ i7-8700T Processor 2.4 GHz		
РСН	Intel Q370		
Memory	Innodisk 8GB SOD DDR4 2133		
SATA port 1	InnDisk 3MG2 SSD 64G		
SATA port 2	Apacer SSD 256G		
DP	Dell U2312		
LAN1 ~ LAN2	LAN (Loopback)		
USB1~USB6	1A 水泥電阻		
COM	Com port loopback		
Operating System	Windows 10 Professional 64-bit		
Test Equipment	FSP060-DBAE1 \ PROVA 11_AC/DC mA clamp meter \ Agilent U1252B		
Test Software	Burnin test v8 、 \ IntelBurnTest 1.9 XTU CPU STRESS,FU MARK		

Power Measure (Full loading )						
Model	Test Voltage	Voltage	Current	Power consumption		
I7-8700T	110V AC	24.15V DC	5.52A	133.3W		

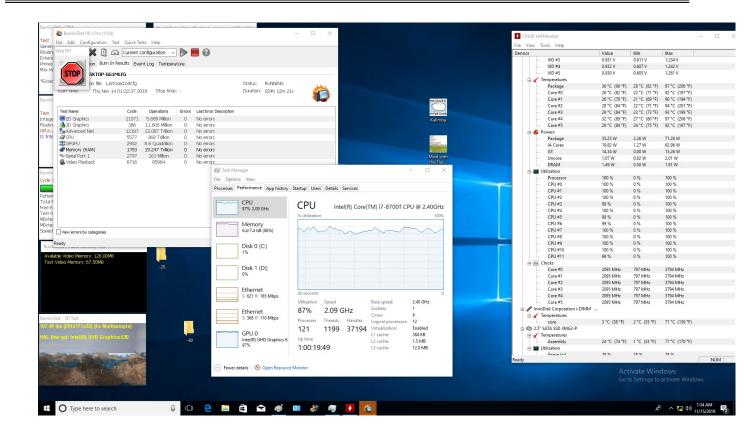
Power Measure ( Hearvy load )								
Item	Voltage/ Condition	S3	S4	S5	Current	Power consumption	Note	
Core I7-8700T Processor	24.15 V	0.08 A	0.09 A	0.08 A	4.6 A	111 W		



## **5. I/O Integrated Stress Test**

System configur	ration							
CPU	auton	Intel® Core™ i7-8700T Pr	rocessor 2 4 GHz					
RAM1		Innodisk 8GB SOD DDR4 2133						
O.S.		Windows 10 SP1 Ultimate Edition 64bit						
		-	1111011 04011					
Temperature		Room temperature						
Testing Utility a	and preference	<u> </u>	t					
Test Software		Test Preference	Test Time(Hours)	Result	Note			
PASSMARK Brur	nIn test (8.1)	Reference below setting	12	PASS				
Test item	Loading (%)	Test preference						
CPU	100	Default preference: Select CPU test types: General p Extension instructions: MMX, CPU affinity: Normal task sched	3DNow!, SSE, SSE2	g Point Unit instructions, Prime	number test			
RAM	100	Default preference: RAM test mode and test patter Test: Default(Cyclic)	n: Standard					
Com Port(s)	100	Default preference: Detect and loopback test Send and receive timeout: 3500 Port speed: 115200 Kbits/Sec	,					
USB	100	Default preference: USB3.0 device loopback						
Video	100	Default preference: Select video playback files: C:\.	\Clock.avi					
2D Graphics	100	Default preference: 2D Graphics Test: All availiable	e Video Memory					
3D Graphics	100	Window placement: Auto place	Default preference: Cest window setup (Multiple monitorof testing): Number of: 1(default) Window placement: Auto placement on primary monitor (default) Window size: 300x200 pixels (default)					
LAN port 1	100	LAN port Loopback						
LAN port 2	100	LAN port Loopback						



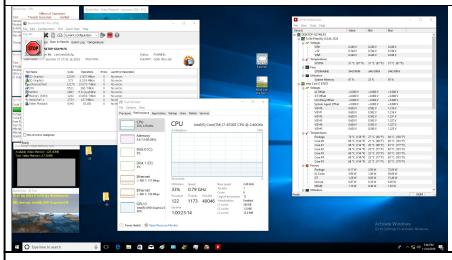




## 6. Temperature Alternate Operation Test

Device Model	ROC286BB	Test Result	PASS	
Dia	agram of curves	Test Tempe	erature	Test Time
Temp (°C)	7	High	60°C	12h
		Low	-40°C	12h
25 1 1	14.5 26.5 / 27.5 Time	Test Standard	Refer IEC60	
-40	(hour)	Test Software	Burnin t	est v8.1

#### Test picture



#### Test procedure

- 1. This operation test is under temperature range  $-40^{\circ}\text{C} \sim 60^{\circ}\text{C}$
- 2. Standards is referred to IEC60068-2-14 Change of temperature
- 3. Have the subject inside the chamber and set up related cables.
- 4. Set up the temperature
- 5. If it's OK then rise up temperature to 60°C and run Burnin test v6.0 for stress test
- 6. Keep unpowered subject for 12 hours on -40°C
- 7. Power on test and Perform minimum 3 power on/off cycles (to be sure that subject can reboot)
- 8. Observe the temperature and the subject in the test execution
- 9. Check the damage on the subject by visual and do function test

#### Note:

#### **Electronic function check:**

- 1. All system functions must be checked with appropriate testing programs and should pass the inspection.
- 2. Running Windows for OS, the system should not have degradation in its performance.

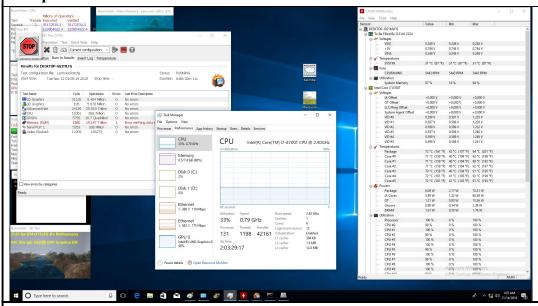
- 1. The connectors and components should work properly without any interference.
- 2. All screws should be tightened up appropriately.



## 7. High Temperature Operating Test

Device Model	ROC286BB	Test Resul	lt I	PASS	
Diagram of curves		Test Temp	Test Time		
60		High	60°C	48Hours	
25		Test Standard	Reference IEC-6006		
1	Time (hour) 49 50	Test Software	Burnin tes	st v8.1	

#### **Test picture**



#### **Test procedure**

- 10. This operation test is under temperature range  $25^{\circ}C\sim60^{\circ}C$
- 11. Standards is referred to IEC60068-2-14 Change of temperature
- 12. Have the subject inside the chamber and set up related cables.
- 13. Set up the temperature
- 14. If it's OK then rise up temperature to 60°C and run Burnin test v6.0 for stress test
- 15. Power on test and Perform minimum 3 power on/off cycles (to be sure that subject can reboot)
- 16. Observe the temperature and the subject in the test execution
- 17. Check the damage on the subject by visual and do function test

#### Note:

#### **Electronic function check:**

- 1. All system functions must be checked with appropriate testing programs and should pass the inspection.
- 2. Running Windows for OS, the system should not have degradation in its performance.

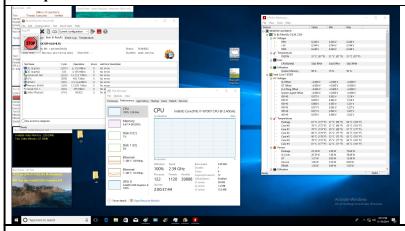
- 1. The connectors and components should work properly without any interference.
- 2. All screws should be tightened up appropriately.



## 8. High Temperature and Humidity Operating Test

Device Model	ROC286BB	Test Result	PAS	S
Diag	ram of curves	Test Tempe	erature	Test Time
95		High	60°C	24Hours
60		Humidity	95%	24110u18
25	Time	Test Standard		rence 0068-2
1	25 26 (hour)	Test Software	Burnin t	test v8.1

#### **Test picture**



#### **Test procedure**

- 18. This operation test is under temperature range  $25^{\circ}C\sim60^{\circ}C$
- 19. Standards is referred to IEC60068-2-3 Change of temperature
- 20. Have the subject inside the chamber and set up related cables.
- 21. Set up the temperature
- 22. If it's OK then rise up temperature to  $60^{\circ}\text{C}$  and run Burnin test v6.0 for stress test
- 23. Power on test and Perform minimum 3 power on/off cycles (to be sure that subject can reboot)
- 24. Observe the temperature and the subject in the test execution
- 25. Check the damage on the subject by visual and do function test
- 26. Humidity: 95%

#### Note:

#### **Electronic function check:**

- 1. All system functions must be checked with appropriate testing programs and should pass the inspection.
- 2. Running Windows for OS, the system should not have degradation in its performance.

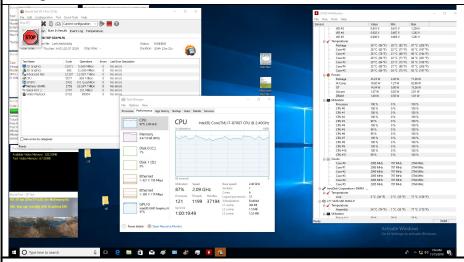
- 1. The connectors and components should work properly without any interference.
- 2. All screws should be tightened up appropriately.



## 9. Low Temperature Operation Test

Device Model	ROC286BB	ROC286BB Test Result		PASS
Diag	Diagram of curves			
Temp (°C) ↑ 25	<i></i>	Low	-40°C	24Hours
	Time (hour)	Test Standard		rence 0068-2
-40	25.5 27	Test Software	Burnin 1	test v8.1

#### **Test picture**



#### **Test procedure**

- 27. This operation test is under temperature range  $25^{\circ}\mathrm{C} \sim \text{-}40^{\circ}\mathrm{C}$
- 28. Standards is referred to IEC60068-2-1 Change of temperature
- 29. Have the subject inside the chamber and set up related cables.
- 30. Set up the temperature
- 31. If it's OK then rise up temperature to -40°C and run Burnin test v6.0 for stress test
- 32. Power on test and Perform minimum 3 power on/off cycles (to be sure that subject can reboot)
- 33. Observe the temperature and the subject in the test execution
- 34. Check the damage on the subject by visual and do function test

#### Note:

#### **Electronic function check:**

- 1. All system functions must be checked with appropriate testing programs and should pass the inspection.
- 2. Running Windows for OS, the system should not have degradation in its performance.

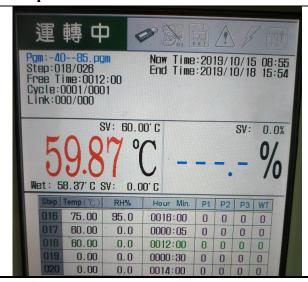
- 1. The connectors and components should work properly without any interference.
- 2. All screws should be tightened up appropriately.



10. High Temperature Power ON/OFF Test

Device Model	ROC286BB	Test Resul	t	PASS	
Dia	gram of curves	Test Temp	erature	Test Time	
<u> </u>	<b>↑</b>				
60		Test Standard	Reference IEC60068		
25			System can times under temperature	~	
1	Time (hour) 49 50	criteria	On/off rule On $\rightarrow$ 10 m Off $\rightarrow$ 40 m Total: 50 m	ninute/time ninute/time	

#### **Test picture**



#### **Test procedure**

- 35. This operation test is under temperature range  $25^{\circ}\text{C} \sim 60^{\circ}\text{C}$
- 36. Standards is referred to IEC60068-2-2 Change of temperature
- 37. Have the subject inside the chamber and set up related cables.
- 38. Set up the temperature
- 39. If it's OK then rise up temperature to 60°C and DOS mode run counter.exe for test
- 40. Unpowered subject should be burn up to 70°C
- 41. Power on test and Perform minimum 3 power on/off cycles (to be sure that subject can reboot)
- 42. Observe the temperature and the subject in the test execution
- 43. Check the damage on the subject by visual and do function test

#### Note:

#### **Electronic function check:**

- 1. All system functions must be checked with appropriate testing programs and should pass the inspection.
- 2. Running Windows for OS, the system should not have degradation in its performance.

- 1. The connectors and components should work properly without any interference.
- 2. All screws should be tightened up appropriately.



11. Low Temperature Power ON/OFF Test

Device Model	del ROC286BB Test Result		lt	PASS	
Diagram of curves		Test Temperature Test Tim			
Temp (°C)		Low	-40°C	7.5Hours	
(°C)↑ 25 ————————————————————————————————————		Test Standard	Reference IEC-600		
	Time (hour)		System ca 10 times u temperatur		
-40 1.5	25.5 27	Criteria	On/off rule On → 10n Off → 40r Total: 50m	nin/time min/time	

#### **Test picture**



### **Test procedure**

- 44. This operation test is under temperature range  $25^{\circ}\text{C} \sim -40^{\circ}\text{C}$
- 45. Standards is referred to IEC60068-2-14 Change of temperature
- 46. Have the subject inside the chamber and set up related cables.
- 47. Set up the temperature
- $48.\;$  If it's OK then rise down temperature to -40°C and DOS mode run counter.exe for test
- 49. Unpowered subject should be cool down to -40°C
- $50.\;$  Keep unpowered subject for four hours on -40°C
- 51. Power on test and Perform minimum 3 power on/off cycles (to be sure that subject can reboot)
- 52. Observe the temperature and the subject in the test execution
- 53. Check the damage on the subject by visual and do function test

#### Note:

#### **Electronic function check:**

- 1. All system functions must be checked with appropriate testing programs and should pass the inspection.
- 2. Running Windows for OS, the system should not have degradation in its performance.

- 1. The connectors and components should work properly without any interference.
- 2. All screws should be tightened up appropriately.



# 12. Thermal Measurement

Test Purpose	The purpose of performing thermal profile test is to identify potential thermal problem of the EUT. And it is to aid products in reliability assessment considering that semiconductor failure rates rise rapidly with increasing junction temperature  In case of systems cooling, patterns will vary with stacking choices, temperature/thermal mapping can aid in the development of optimum tacking arrangements								
Test Equipment	XSON THS-B4T-150 Chamber YOKOGAWA MV1000, Thermometer (FLUKE50D K/J) Infrared thermal imaging camera Model TVS-200EX Inimum 1 Set								
Quantity Tested	inimum 1 Set								
Test Software	Passmark Burn-In Test under Windows 10								
Test Procecedure	<ol> <li>Thermal pre-scan measurement:         Temperature: 24~26°C/40~60%RH         Capture thermal IR photo for whole boards after the EUT execute passmark burn-in test with 100% lading during 1 hour at least.</li> <li>Thermal actual measurement:         a. Select the test points according to the IR photo and attach thermocouples to the hot points b. Put the EUT in thermal chamber and set the temperature profile of as test specification         c. Turn on the thermal chamber and power on the EUT to enter windows environment to run Max Power Test + 3DMARK 2003 application program         d. After the EUT executing the test software for 4 hours, record thermal maximum value for each thermocouples point.         e. Turn off the thermal chamber and EUT         f. Verify and check recorded figure of each components to its' operating temperature range listed in specification/approval sheet of each measured component</li> </ol>								
Test diagram of curves	Temp (°C)  60  55								
Test picture									



# Thermal point





# **Test Result**

Point		-40°C	-20°C	0℃	25℃	<b>40℃</b>	<b>50℃</b>	<b>55℃</b>	60℃
C	CPU Frequency( GHz)	2.8	2.8	2.8	2.7	2.39	2.39	0.79	0.79
	CPU T-J (℃)	36	45	36	71	71	77	71	72
1	CPU Die	21	29.1	18.3	58.4	61.4	68.3	71	72
2	CPU Heatsink	16	25.2	14.7	54.3	58.7	65.6	70	71
3	DRAM	1	11.2	26.6	75.9	72.1	78.6	84	89.8
4	РСН	19	29.5	42.3	86.7	86.5	90.8	95	100.6
5	Left Heatsink(PCIE)	-25	-15.8	8.9	51	50	58.4	64	68.6
6	Right Heatsink(CPU)	-23	-13.7	5.6	53.4	51.5	59.6	64	69.8
7	Left Power	-21	-11.8	10.1	49.1	48.6	58.4	63	68.8
8	Right Power	-21	-11.1	10	49.6	48.3	58.1	63	68.8
9	SSD1	-20	-16	4.5	44.1	41.1	52.4	57	63.2
10	SSD2	-20	-16.2	4.5	43.6	41.1	52.1	57	62.8
	I219 LAN (Mb)	945	949	944	937	940	939	939	939
	I210 LAN (Mb)	952	943	952	944	943	947	947	946
Iı	nnodisk 3MG2-P 64G ( Read/Write MB )	503/161	413/182	502/199	503/198	502/197	507/198	508/197	505/197
	Apacer SSD 256G ( Read/Write MB )	276/157	284/327	287/321	287/330	284/332	285/330	286/328	284/326